# Electron-beam positive tone resist gL2000

2015.02.19 Ver.7





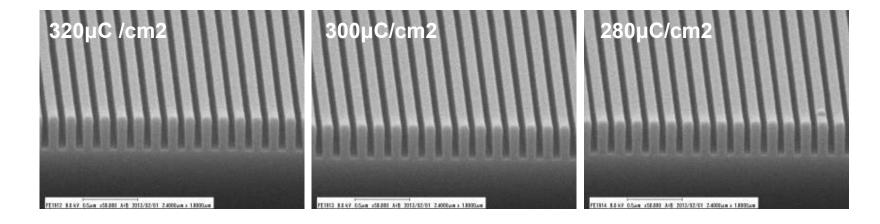
# gL2000 Performance



- High speed, high resolution resist
- Tunable develop process
- High resolution developer available
- High dry etch resistance (Superior to PMMA)



# Dose margin Developer: gL Developer

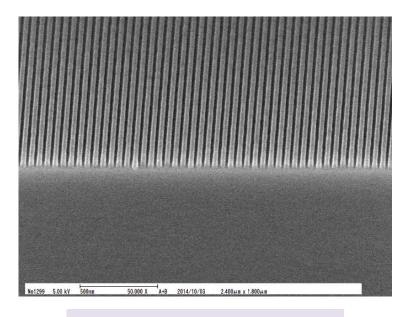


100kV 50pA Pitch150nm/space50nm

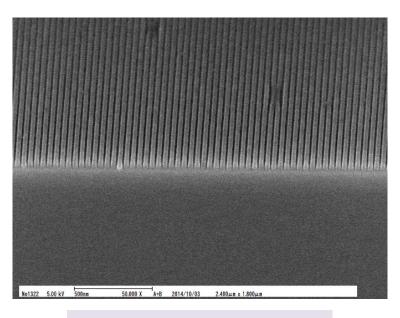








Pitch50nm/space16.25nm



Pitch40nm/space12.5nm

Film thickness:60nm 100kV 10pA

Developer :gL Developer @RT × 30sec.

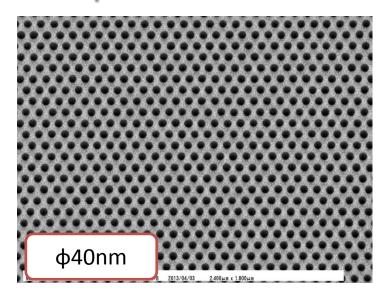


### Dot pattern & Donut pattern

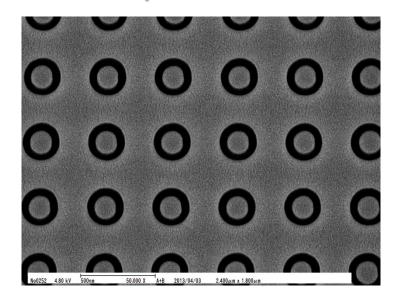
Film thickness :230nm 100kV 50pA

Developer :gL Developer @RT 120sec

#### Dot pattern



#### Donut pattern

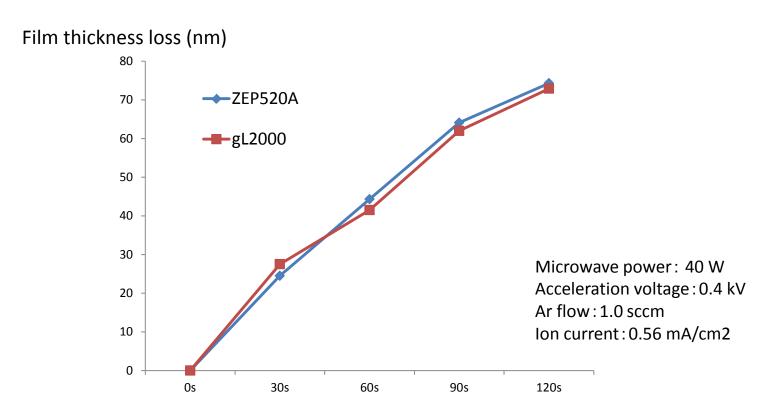






Compared to leading competitor

Ar (Argon)

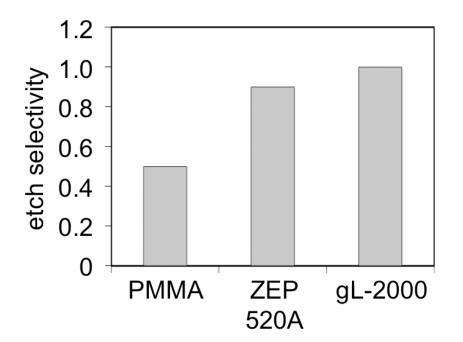






Compared to leading competitor and PMMA

CF<sub>4</sub> (Reactive-ion-etch process)



CF<sub>4</sub> flow: 15 sccm Power: 75 W

Pressure: 10mTorr Voltage: 110V DC

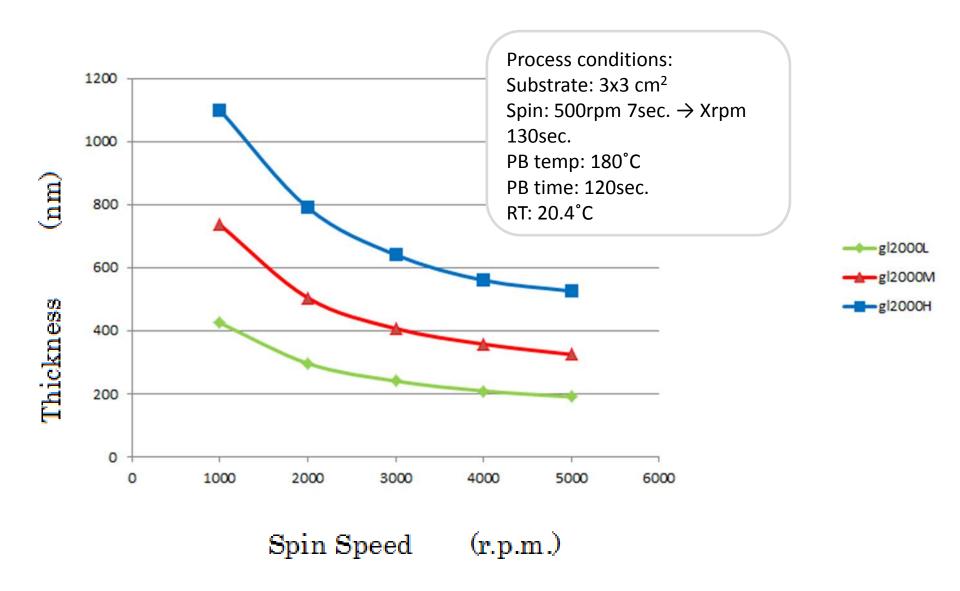
Time: 60 s

Etch Selectivity of PMMA, ZEP 250A and gL2000 vs. SiO<sub>2</sub>. The difference in etch selectivity values for ZEP 250A and gL2000 is within the margin of error of the measurement.

<sup>\*\*</sup> Data courtesy of R. G. Hobbs, M. K. Mondol and K. K. Berggren, Research Laboratory of Electronics, Massachusetts Institute of Technology

## gL2000 Spin curve





# gL2000 Line-up



Resist: gL2000-L, M, H

Package Sizes: -100ml -946ml (Quart)

**Developer**: gL Developer (Standard Developer)

: gL Developer HR (High Resolution Developer)

**Rinse** : gL Rinse

**Remover**: gL Remover

Available in 4 liter containers

